United States Patent [19]

Arnoux et al.

[11] **Patent Number: Des. 288,301**

[45] **Date of Patent: ** Feb. 17, 1987**

[54] **CLAMP-ON CURRENT PROBE**

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[73] Assignee: **Construction d'Appereillage,** Paris, France

[**] Term: **14 Years**

[21] Appl. No.: **620,891**

[22] Filed: **Jun. 15, 1984**

[30] **Foreign Application Priority Data**

Dec. 21, 1983 [FR] France 834792

[52] **U.S. Cl.** **D10/79**

[58] **Field of Search** .... D10/46, 75–80, D10/103; 324/72.5, 127, 129, 156, 158 P

[56] **References Cited**

U.S. PATENT DOCUMENTS

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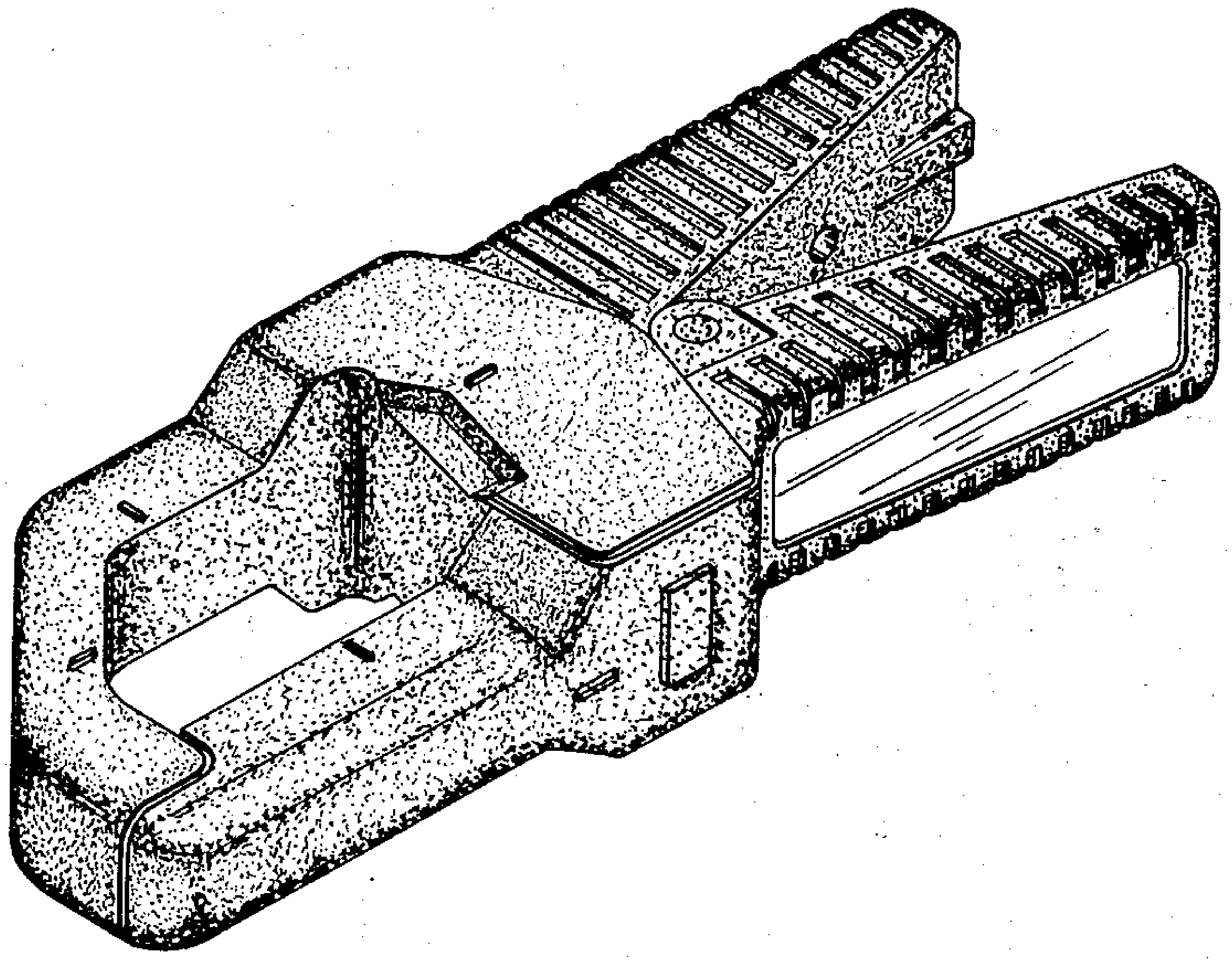
[57] **CLAIM**

The ornamental design for a clamp-on current probe, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a clamp-on current probe showing our new design;
FIG. **2** is a top plan view thereof;
FIG. **3** is a left side elevational view thereof;
FIG. **4** is a bottom plan view thereof;
FIG. **5** is a rear elevational view thereof; and
FIG. **6** is a front elevational view thereof.



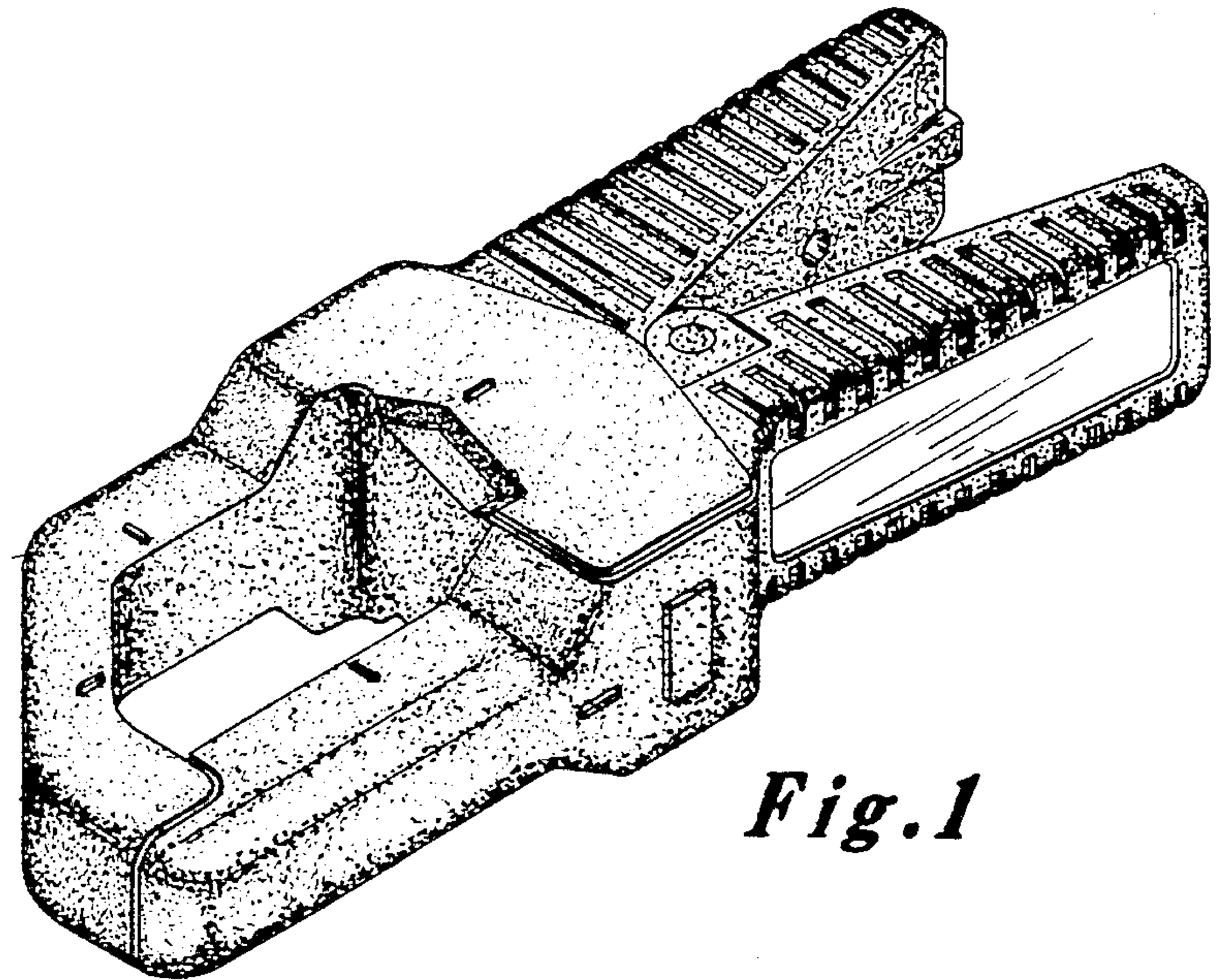


Fig.1

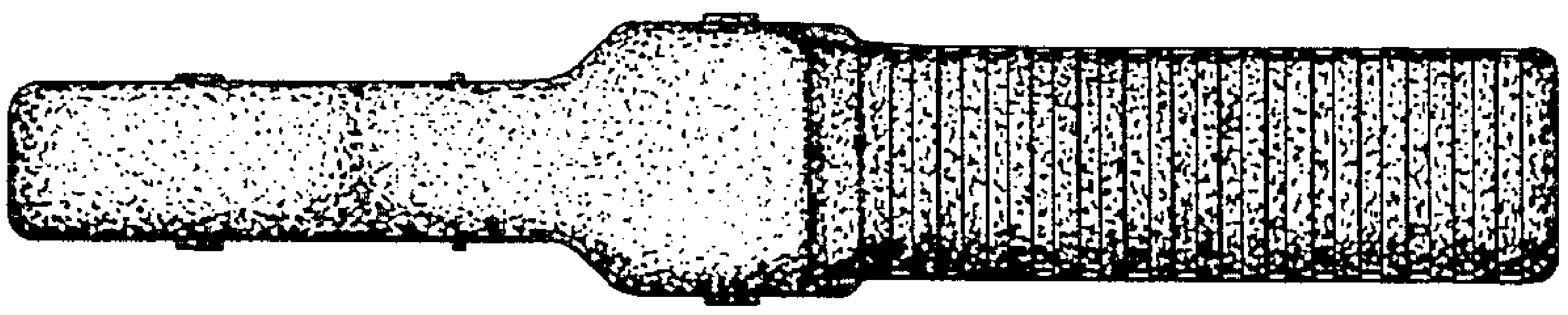


Fig.2

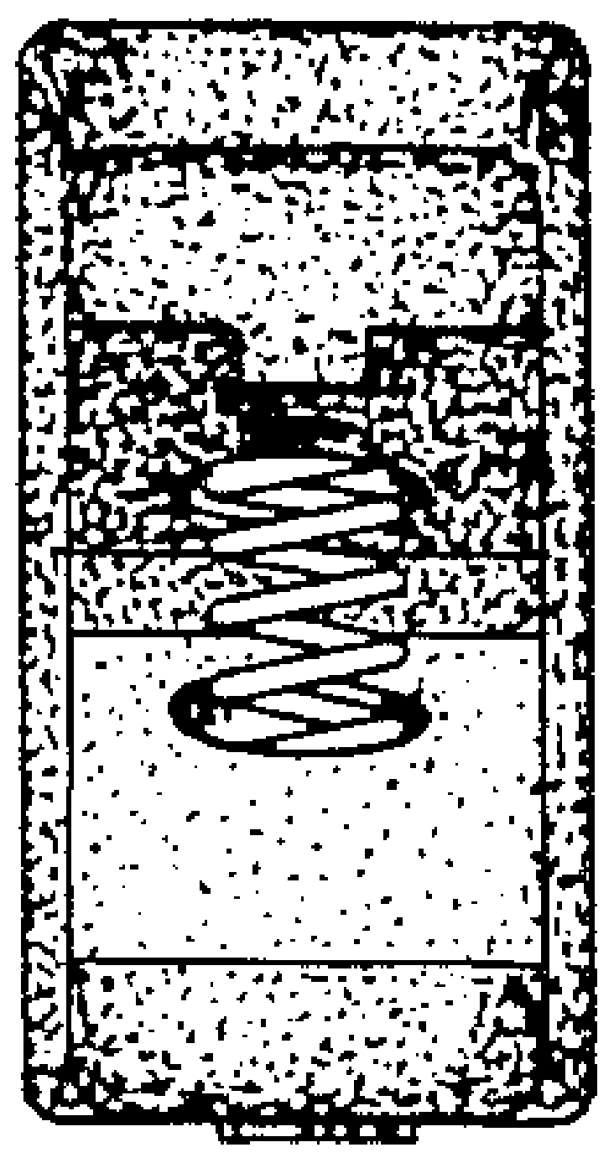


Fig.5

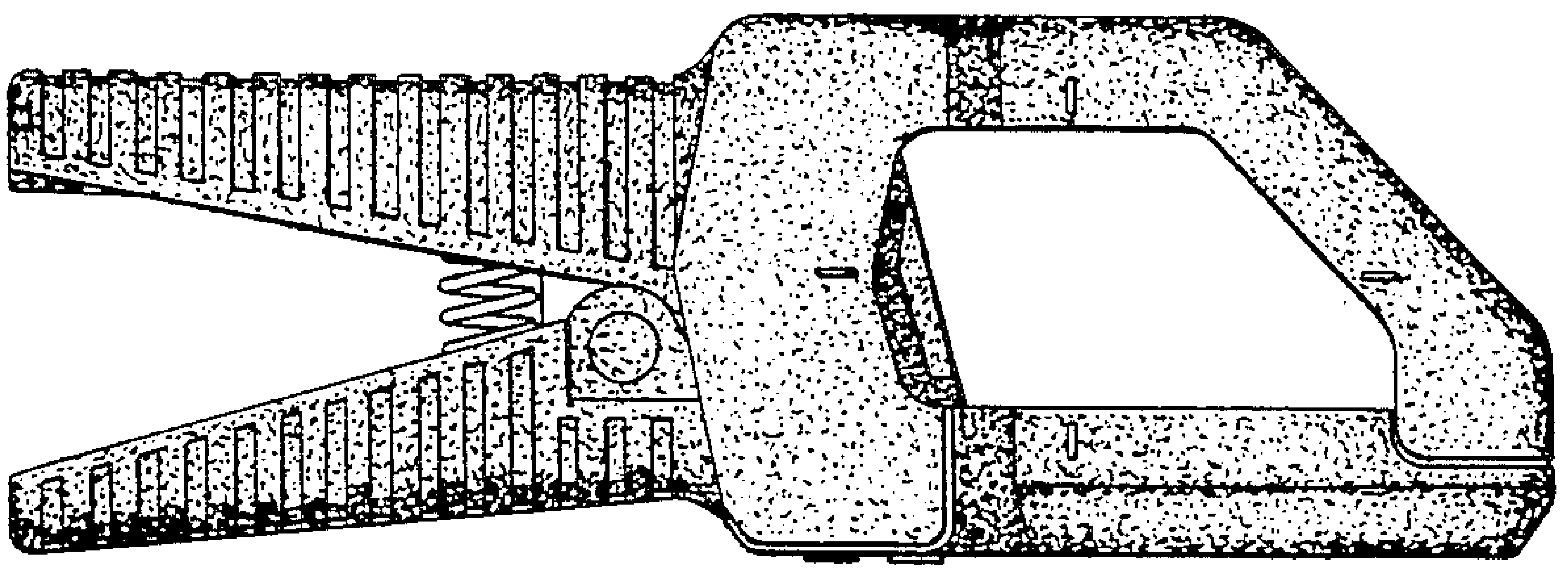


Fig.3

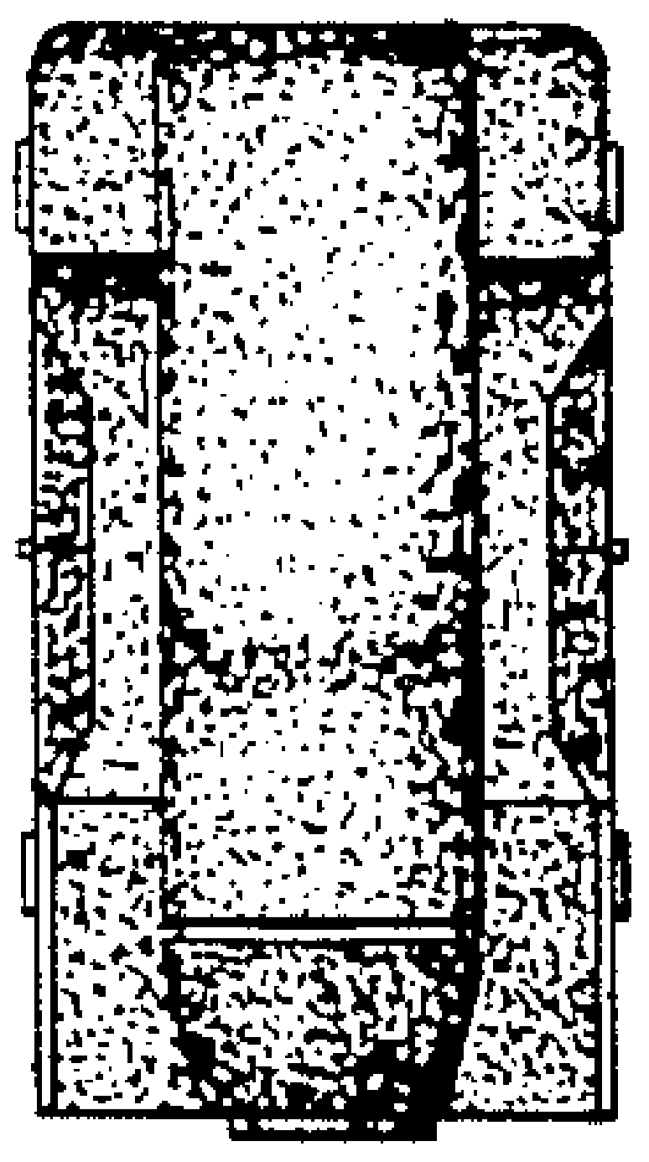


Fig.6

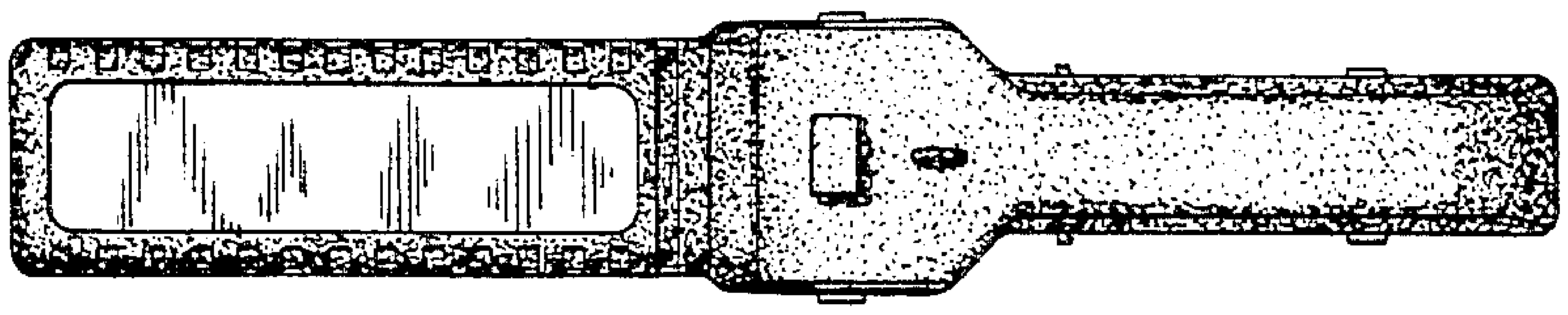


Fig.4